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(12) **United States Design Patent**  
**Ito et al.**

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(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

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**Related U.S. Application Data**

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(30) **Foreign Application Priority Data**

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(51) **LOC (10) Cl.** ..... **24-02**

(52) **U.S. Cl.**  
USPC ..... **D24/225**

(58) **Field of Classification Search**  
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422/560-566, 68.1, 69, 547; 435/288.4,  
435/288.3, 289.1, 283.1, 288.2, 288.5;  
436/44, 46  
CPC ..... B01J 19/0046; B01J 2219/00596;  
G01N 1/405; G01N 35/00009; G01N 1/312;  
B01L 2300/0816; B01L 2400/0406; B01L  
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B01L 9/00; B01L 3/5085; B01L 3/5027;  
A61B 5/1427; C12M 1/28; C12M 1/22;  
C12M 27/02

See application file for complete search history.

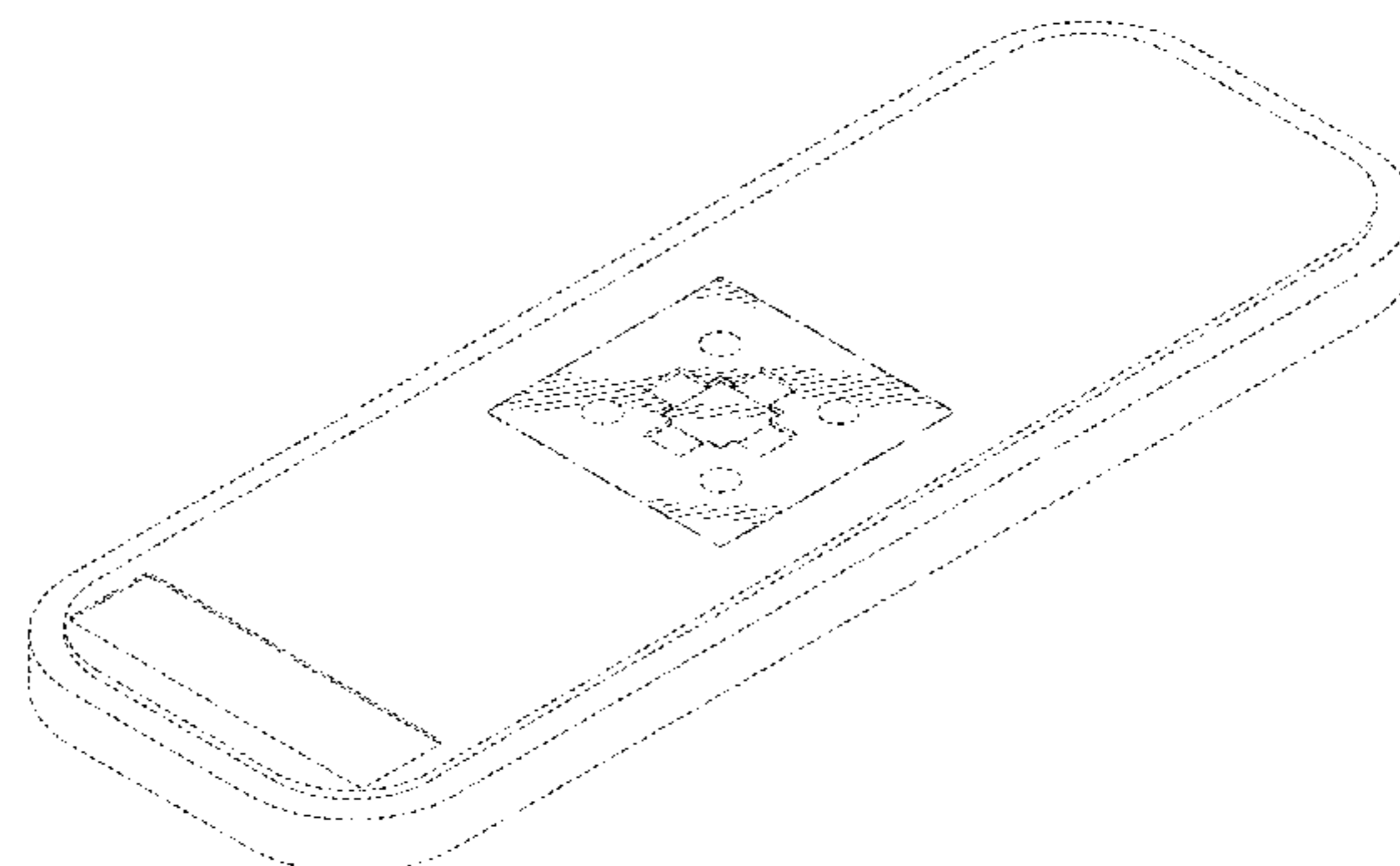
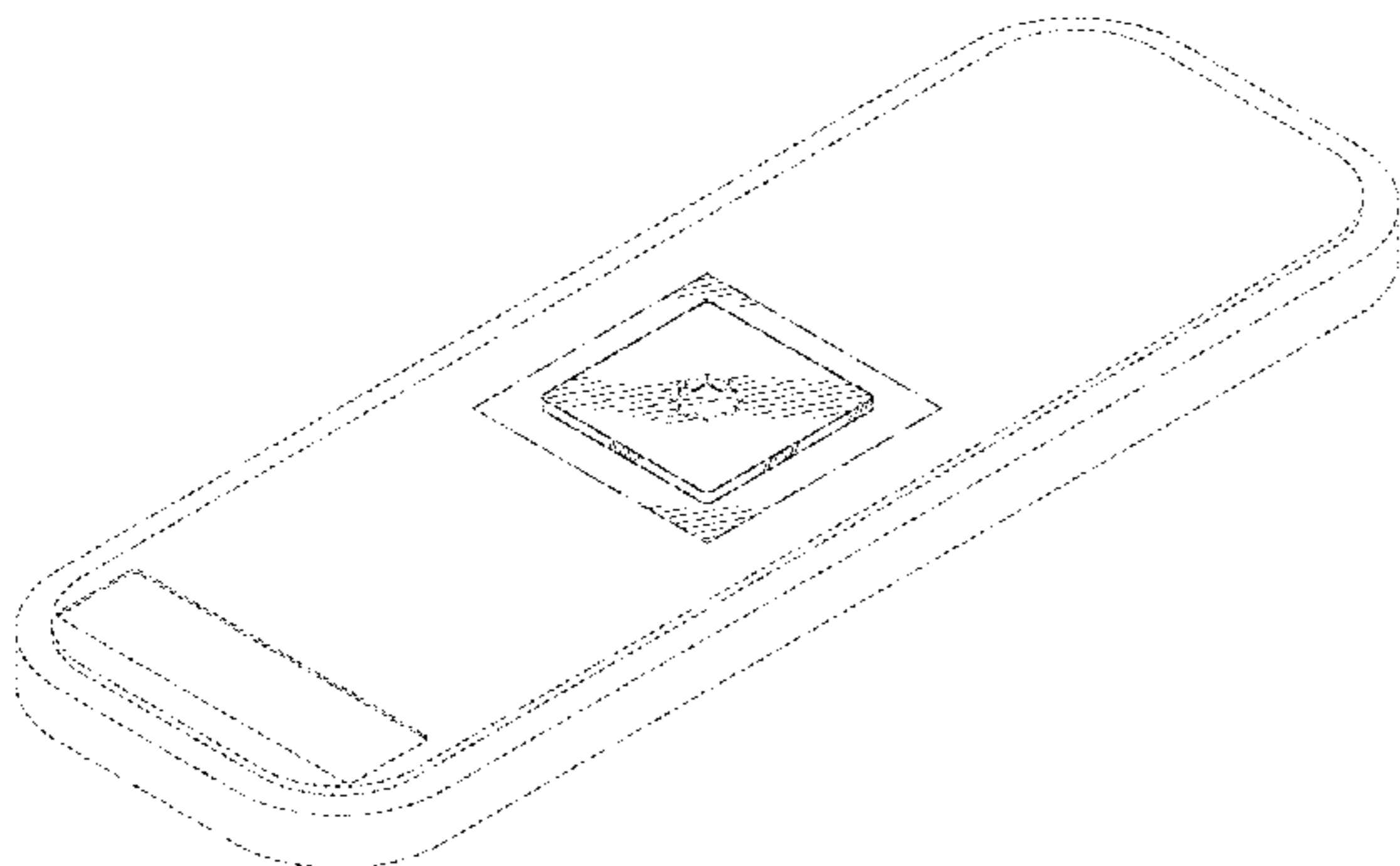
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LLP

(57) **CLAIM**

The ornamental design for a substrate for spectroscopic  
analysis, as shown and described.

**DESCRIPTION**

FIG. 1 is a front view of a substrate for spectroscopic analysis  
of our new design.  
FIG. 2 is a rear view of the substrate for spectroscopic analy-  
sis of FIG. 1.  
FIG. 3 is a top plan view of the substrate for spectroscopic  
analysis of FIG. 1.  
FIG. 4 is a bottom view of the substrate for spectroscopic  
analysis of FIG. 1.

FIG. 5 is a right side view of the substrate for spectroscopic  
analysis of FIG. 1.

FIG. 6 is a left side view of the substrate for spectroscopic  
analysis of FIG. 1.

FIG. 7 is a perspective of the substrate for spectroscopic  
analysis of FIG. 1.

FIG. 8 is a top plan view without the cover part of the substrate  
for spectroscopic analysis of FIG. 1.

FIG. 9 is a perspective view without the cover part of the  
substrate for spectroscopic analysis of FIG. 1.

FIG. 10 is a sectional view taken along the line 10-10 of the  
substrate for spectroscopic analysis of FIG. 3.

FIG. 11 is a sectional view taken along the line 11-11 of the  
substrate for spectroscopic analysis of FIG. 1.

FIG. 12 is a sectional view taken along the line 12-12 of the  
substrate for spectroscopic analysis of FIG. 8.

FIG. 13 is an enlarged sectional view taken along the line  
13-13 of the substrate for spectroscopic analysis of FIG. 10;  
and,

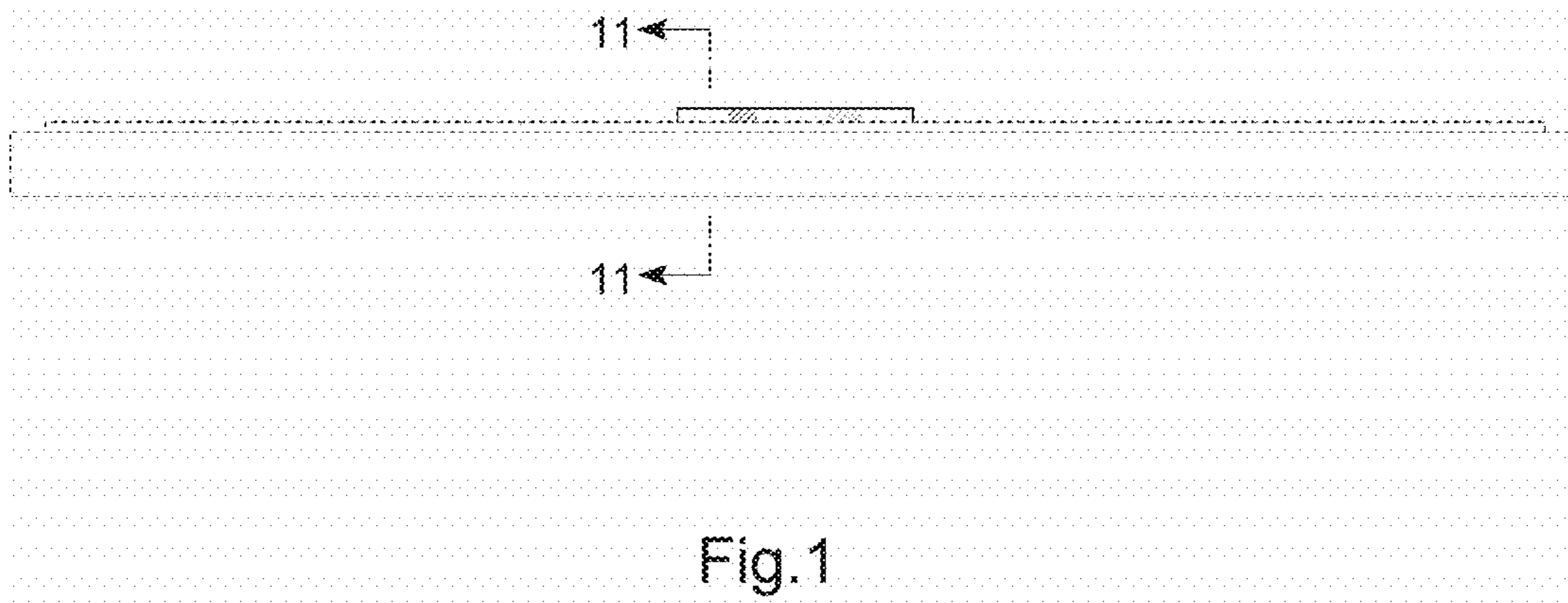
FIG. 14 is a reference sectional view taken along the line  
10-10 of the substrate for spectroscopic analysis of FIG. 3 in  
use, wherein the element is inserted in the concave part for  
element and the glass plate is set above the cover part.

The features shown in dotted lines depict environmental sub-  
ject matter only and form no part of the claimed design.

The broken lines having alternating long and short segments  
define bounds of the claimed design and form no part thereof.

The whole of the substrate for spectroscopic analysis is trans-  
parent.

**1 Claim, 14 Drawing Sheets**



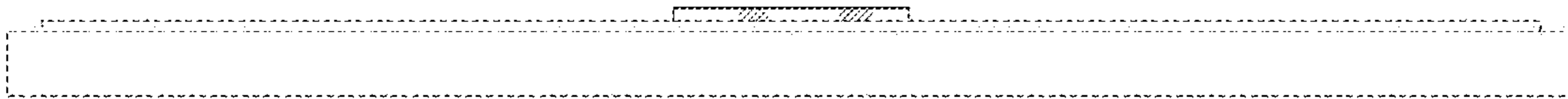


Fig.2

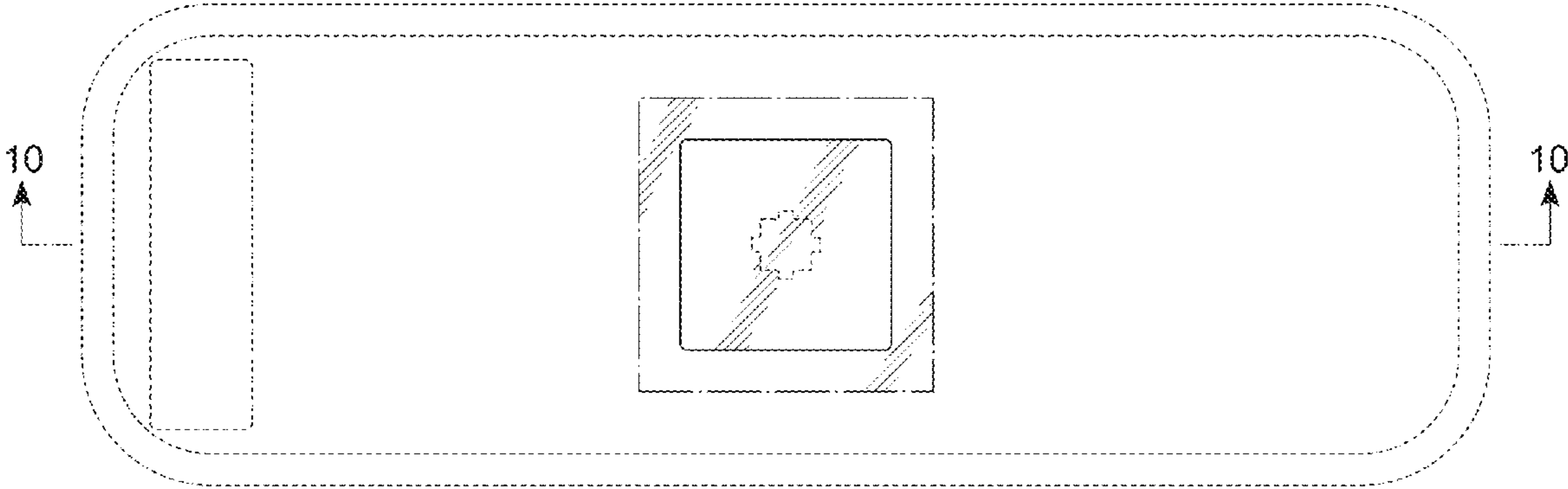


Fig.3

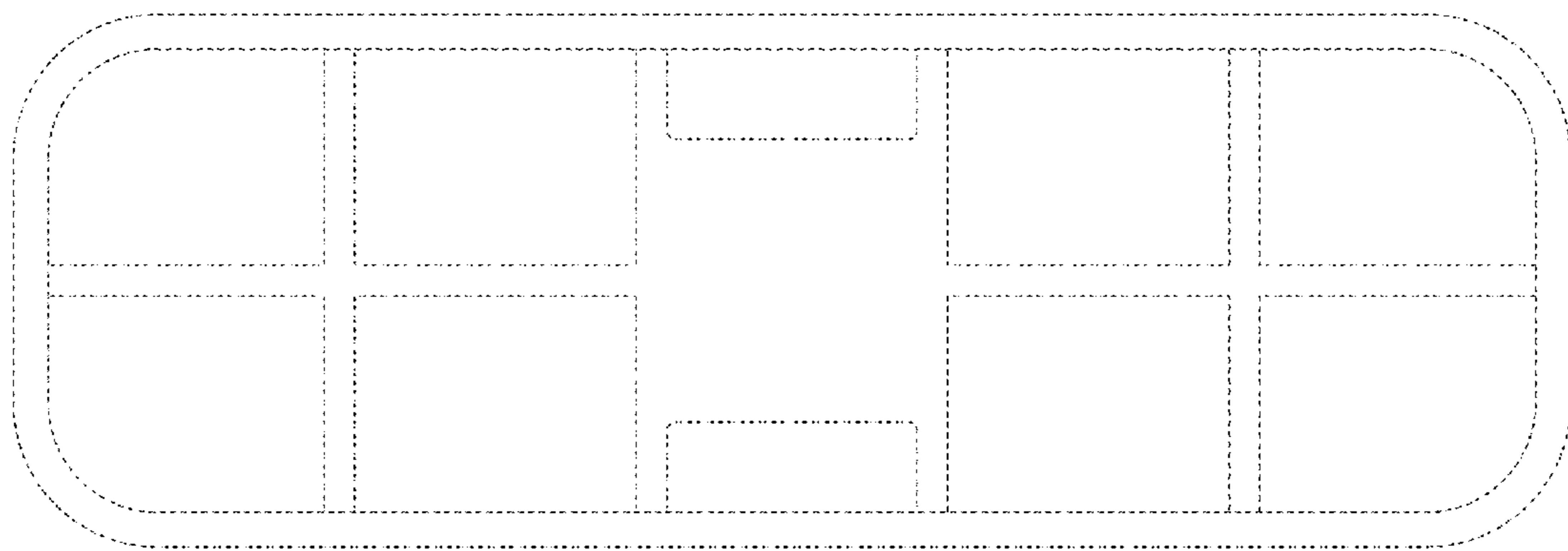


Fig.4

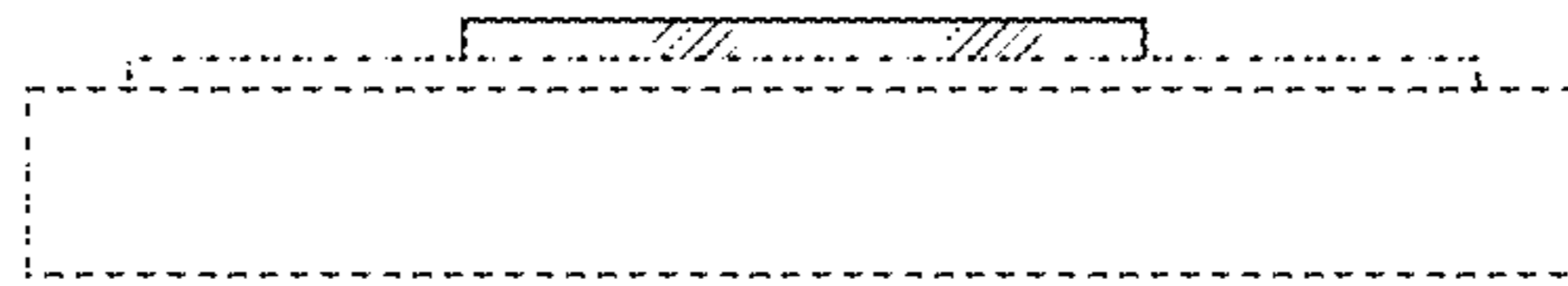


Fig.5

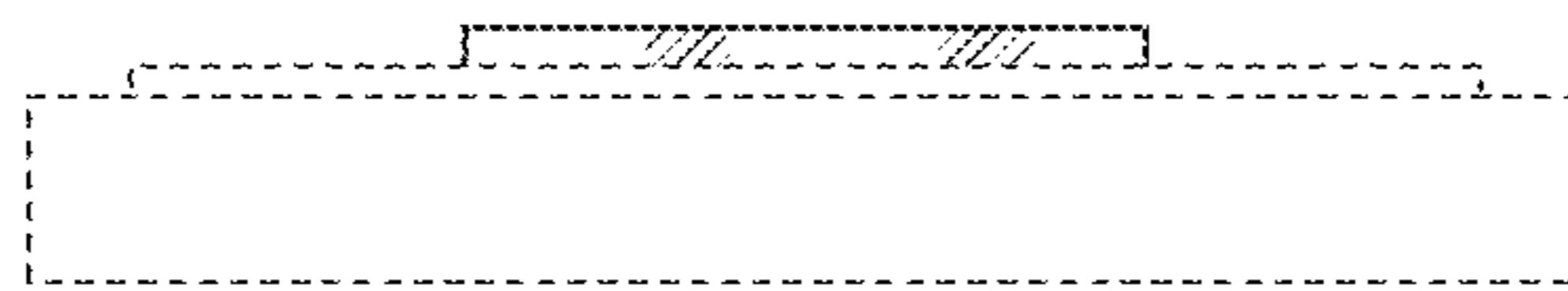


Fig.6



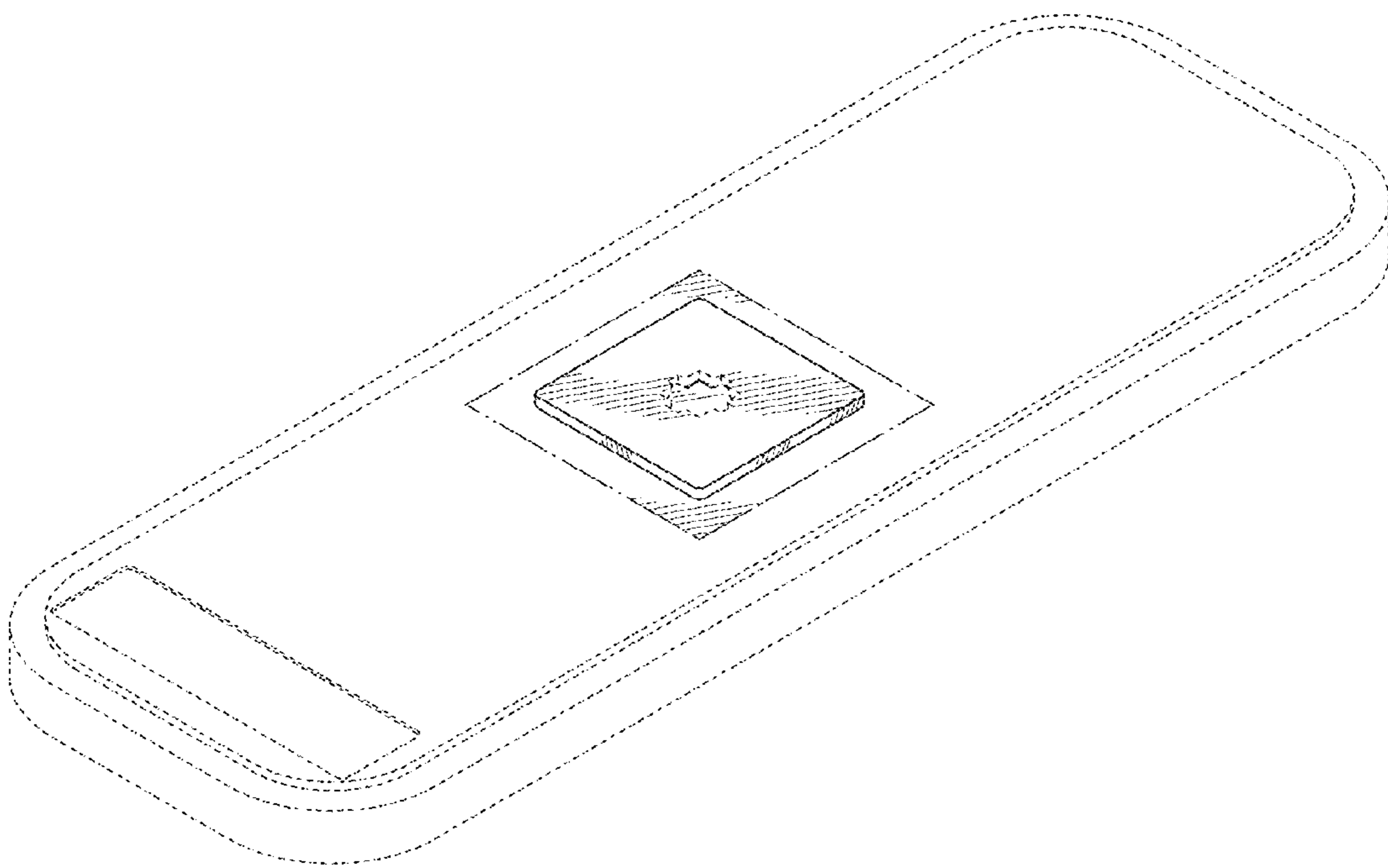


Fig.7

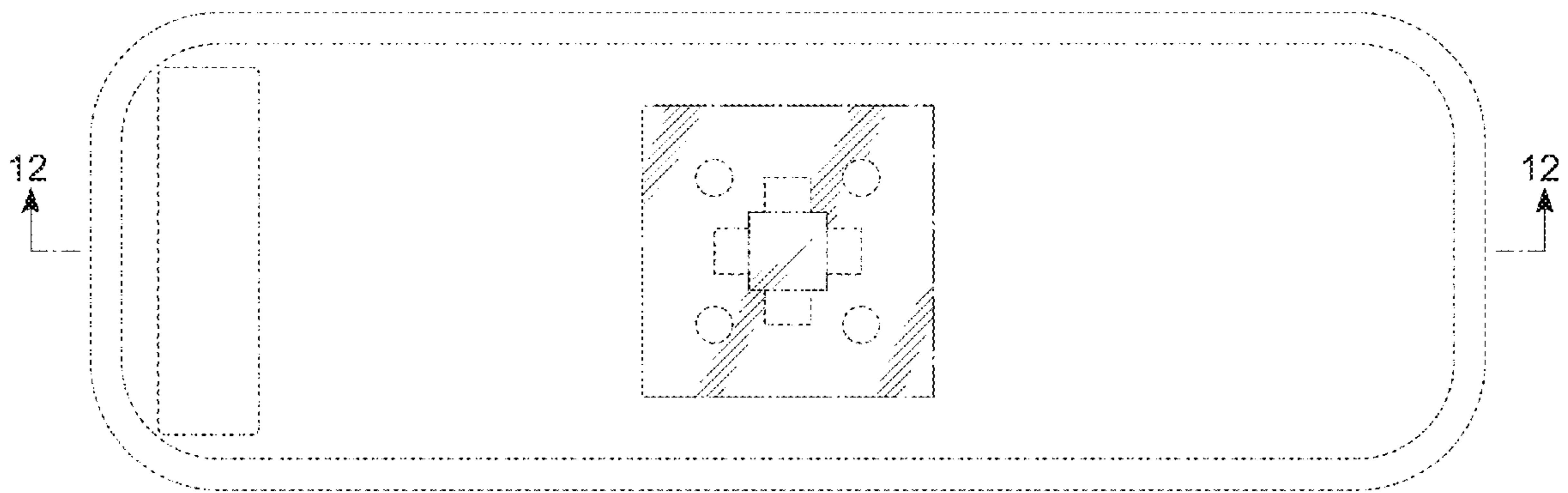


Fig.8

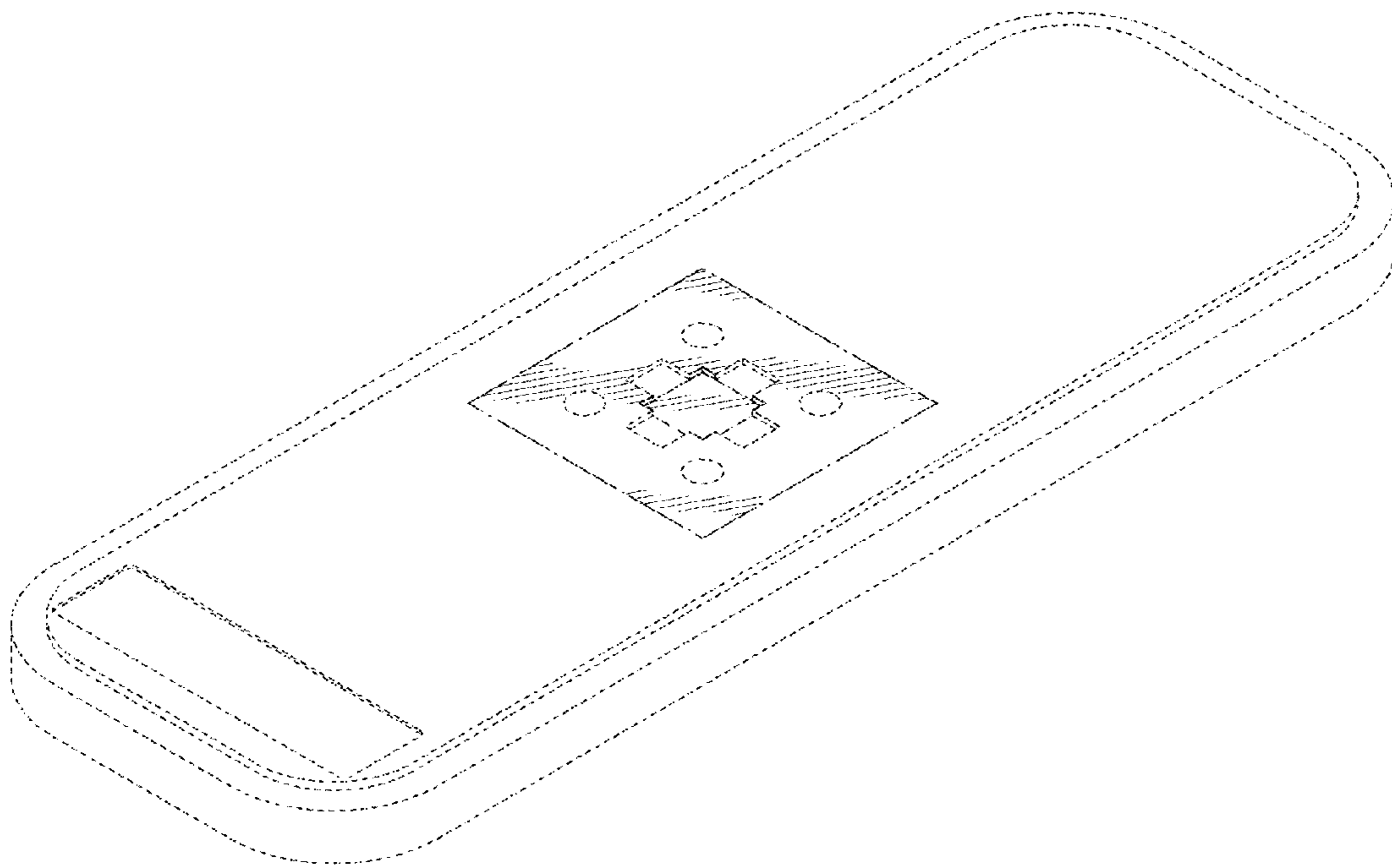


Fig.9

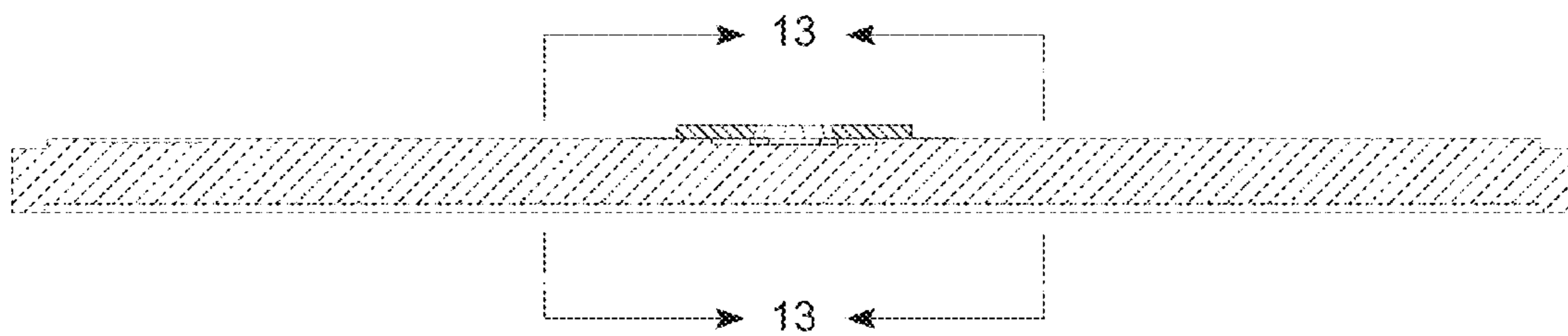


Fig.10

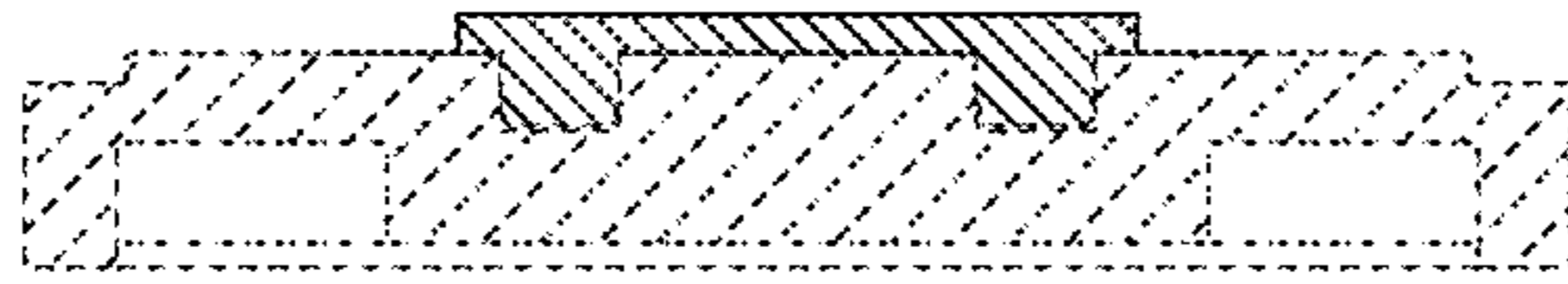


Fig.11

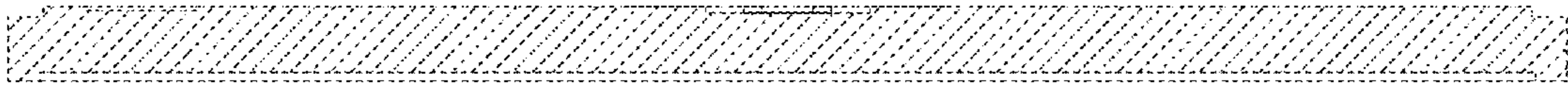


Fig.12

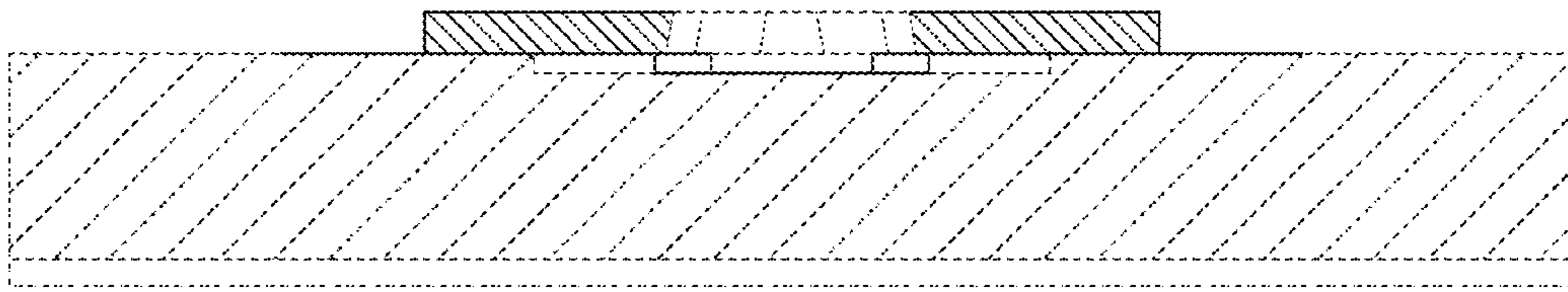


Fig.13

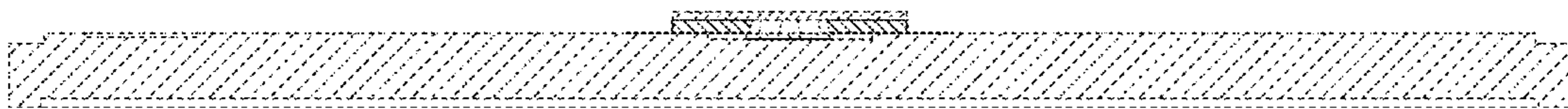


Fig.14